

Notice of References Cited

Application/Control No.

09/502,675

Applicant(s)/Patent Under
Reexamination
Yamazaki et al.

Examiner

Evan T. Pert

Art Unit

2813

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U.S. PATENT DOCUMENTS

*		Document Number	Date	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY			
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	B	US-5,706,064	01-1998	Fukunaga et al.	--	--
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hatano et al. "A NOVEL Self-aligned Gate-overlapped LDD poly-Si TFT with High Reliability and Performance", 1997, IEEE, IEDM, pages 523-526.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.